

Remarks

Applicant thanks the Examiner for the careful examination of this application and the clear explanation of the rejections.

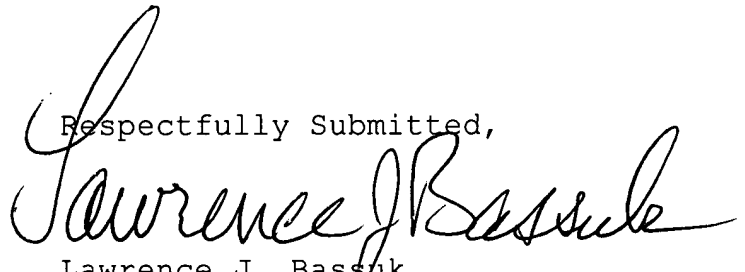
The new title better reflects the claimed matter.

New claims 7-13 better describe the claimed invention.

US 5,606,566 fails to disclose a scan test port or connection circuitry between a test access port and a scan test port. These are positively recited structural elements of the present claims.

The application is in allowable form and the claims distinguish over the cited references. Applicant respectfully requests reconsideration or further examination of this application.

Respectfully Submitted,



Lawrence J. Bassuk
Reg. No. 29,043
Attorney for Applicant

Texas Instruments Incorporated
P. O. Box 655474, MS 3999
Dallas, Texas 75265
972-917-5458